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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE										ATTY. DOCKET NO. 37,248.02				
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W6	AB	3	5	6	5	7	9	3	2/23/71	Herbstman et al.	208	208-	PEIV	
we	AC	3	5	9	5	7	7	8	7/27/71	Smetana et al.	208	2 % EP	2 0 20r	11
WB	AD	3	8	1	6	3	0	1	6/11/74	Sorgenti	208	208		
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WG	AF	3	8	4	7	8	0	0	11/12/74	Guth et al.	208	236		
WG	AG	4	4	9	4	9	6	1	1/22/85	Venkat et al.	C10L 1	30		
WG	AH	4	7	2	3	9	6	3	2/9/88	Taylor	C10L 1	18		
WG	Al	4	8	3	0	7	3	3	5/16/89	Nagju et al.	C01B 17	00 18		
WG	AJ	5	2	4	7	5	9	6	9/15/92	Kukes et al. Durante	C10G 47	3		
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF DOCUMENTS CITED BY APPLICANT

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* EXAMINER: Initial if referenc considered, whether or n t citation is in conformanc with MPEP 609; draw lin thr ugh citation if no in conformance and not considered. Include c py of this form with next communication to applicant.